Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/667,740	BAILEY ET AL.	
Examiner	Art Unit	
TuyetLien (Lien) T. Tran	2179	

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	SEARCHED			
Class	Subclass	Date	Examiner	
715	735	1/3/2006	тт	
709	220	1/3/2006	П	
709	221	1/3/2006	Π	
709	222	1/3/2006	П	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO' (INCLUDING SEARCH)
	DATE	EXMR
Attached EAST search history and inventors name search	1/8/2006	TT
Consulted with Ba Huynh	1/4/2006	тт
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